

Search Notes



Application/Control No.

09/764,787

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

SCHWARTZ ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	03 04 10/05	an
(e-)	26	↓	↓
	14		
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	9	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
	03 04	an ↓
I US	10/05	an
Patent PG Pub	↓	↓
II FOREIGN		
III NPL		
1. Ftext1 2. Ftext2 3. Ntext		
Reviewing Parent 09/764,787	↓	↓
Reviewing (102) 101 Rej w/ Johnson	↓	↓